

## Second Generation Model-based Testing

Provably Strong Testing Methods for the Certification of Autonomous  
Systems

Part III of III –

Complete Test Suites for CSP Refinement

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# Finite Complete Test Suites for CSP Refinement Testing\*

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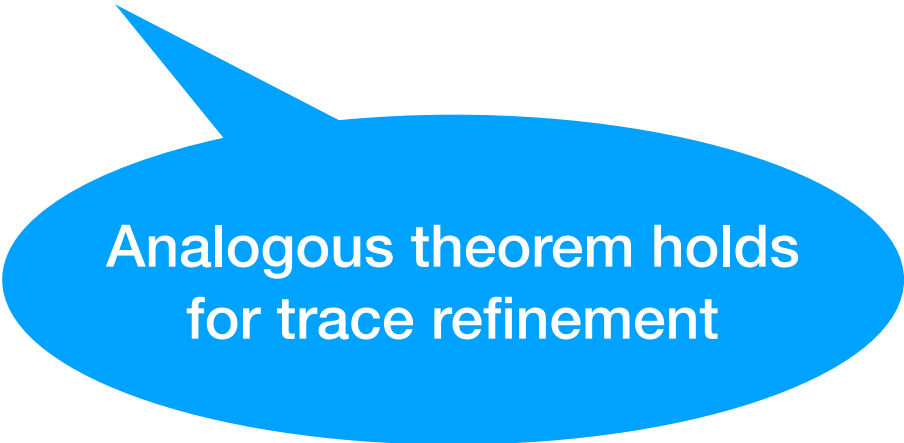
\*The results presented here have been submitted to Science of Computer Programming

# Completeness Result

**Theorem.** Let  $P$  be a non-terminating, divergence-free CSP process over alphabet  $\Sigma$  whose normalised transition graph  $G(P)$  has  $p$  states. Define fault domain  $\mathcal{D}$  as the set of all divergence-free CSP processes over alphabet  $\Sigma$ , whose transition graph has at most  $q$  states with  $q \geq p$ . Then the test suite

$$TS_F = \{U_F(j) \mid 0 \leq j < pq\}$$

is complete with respect to  $\mathcal{F} = (P, \sqsubseteq_F, \mathcal{D})$ .



Analogous theorem holds  
for trace refinement

# Recall

- **Complete test suites**
  - are specified for a given conformance relation
  - accept every conforming implementation
  - reject every non-conforming implementation

# Recall

- **Fault domain.** A collection of models that may or may not conform to a reference model
- **Finite complete black-box test suites**
  - are specified with respect to a fault domain
  - guarantee completeness provided that the true SUT behaviour is reflected by a member of the fault domain
  - provide a **conformance proof** with finitely many finite test cases

# Motivation

- Finite complete test suites are of high interest, because they
  - can **establish full conformance**, provided that the SUT behaviour is captured by the fault domain
  - still possess **high test strength for SUTs outside the fault domain** (experimental evidence)
  - still have manageable size if **equivalence class partitioning methods** are applied

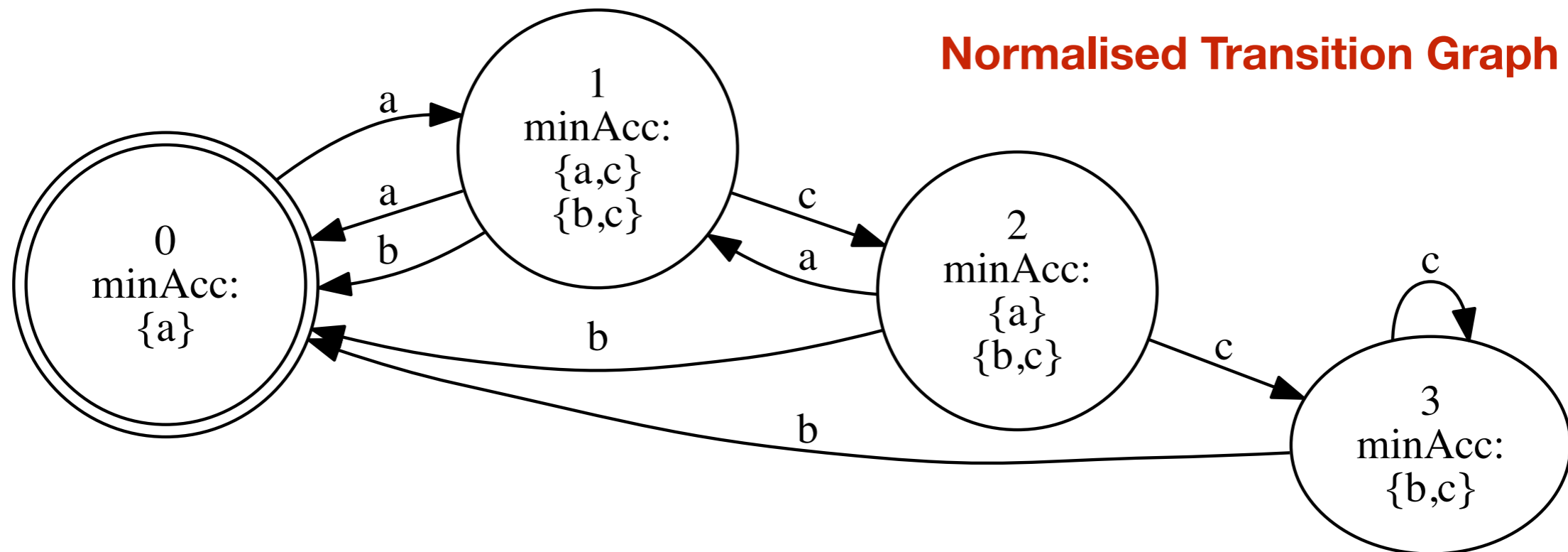
# Failures Semantics – Representation of Finite-State Processes

$$P = a \rightarrow (Q \sqcap R)$$

$$Q = a \rightarrow P \sqcap c \rightarrow P$$

$$R = b \rightarrow P \sqcap c \rightarrow R$$

**A. W. Roscoe**, Model-checking CSP, in: A. W. Roscoe (Ed.), A Classical Mind: Essays in Honour of C. A. R. Hoare, Prentice Hall International (UK) Ltd., Hertfordshire, UK, UK, 1994, Ch. 21, pp. 353–378.

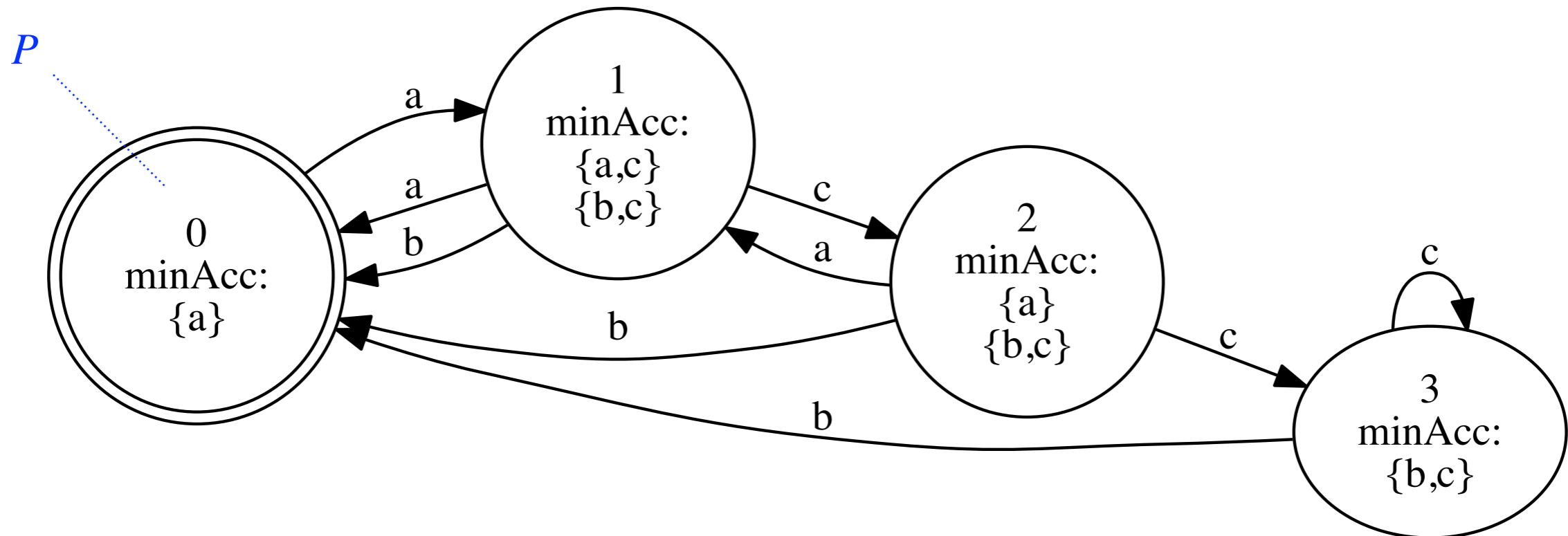


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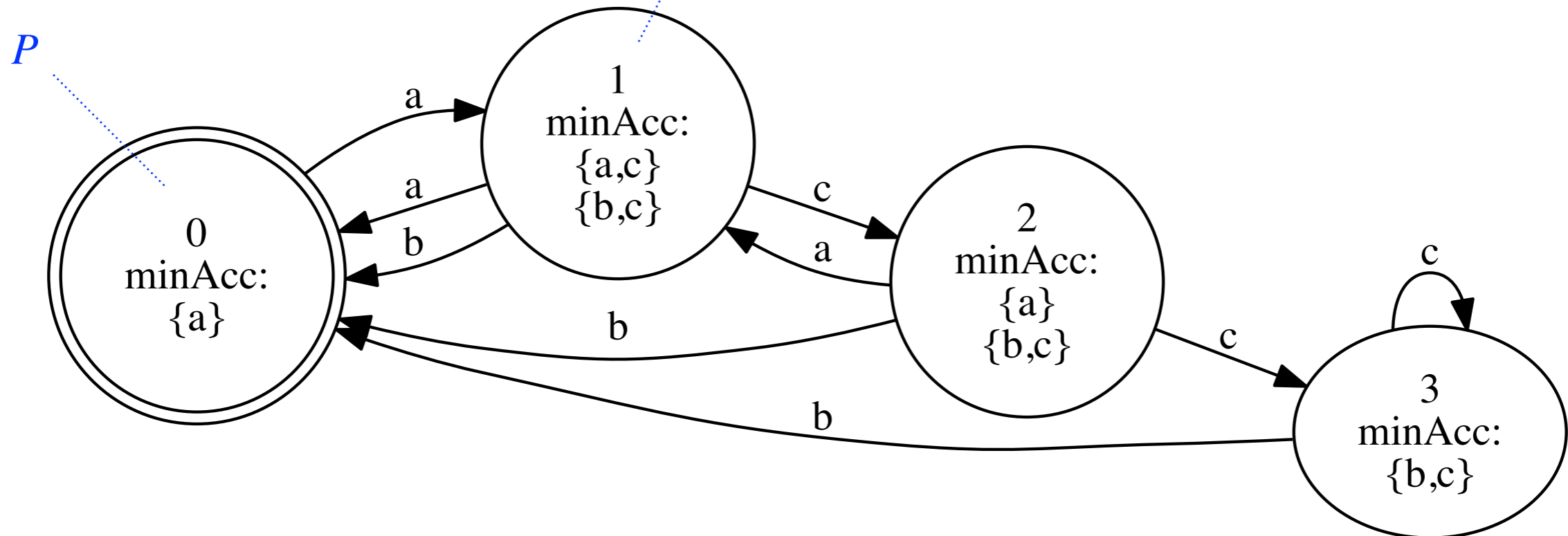
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$$P/a = Q \sqcap R$$

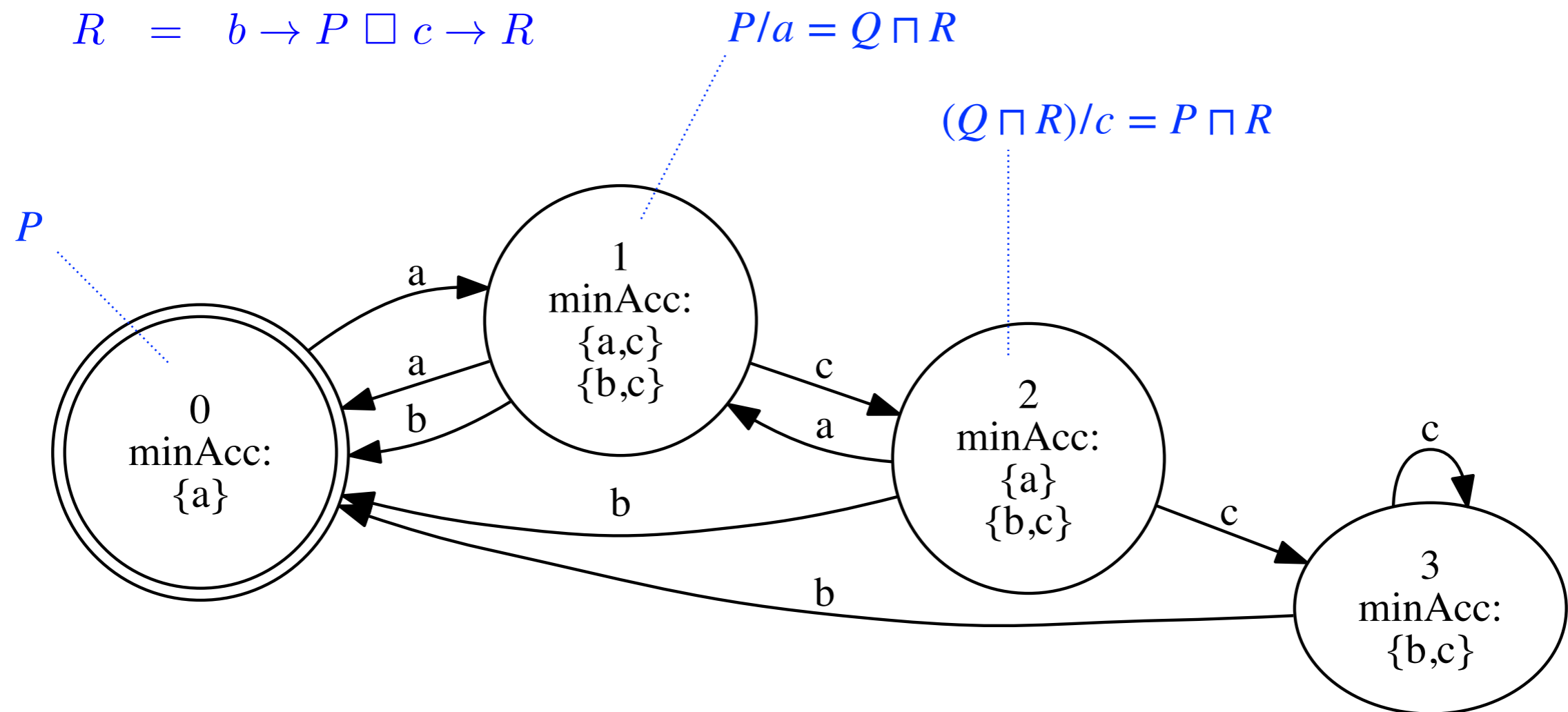


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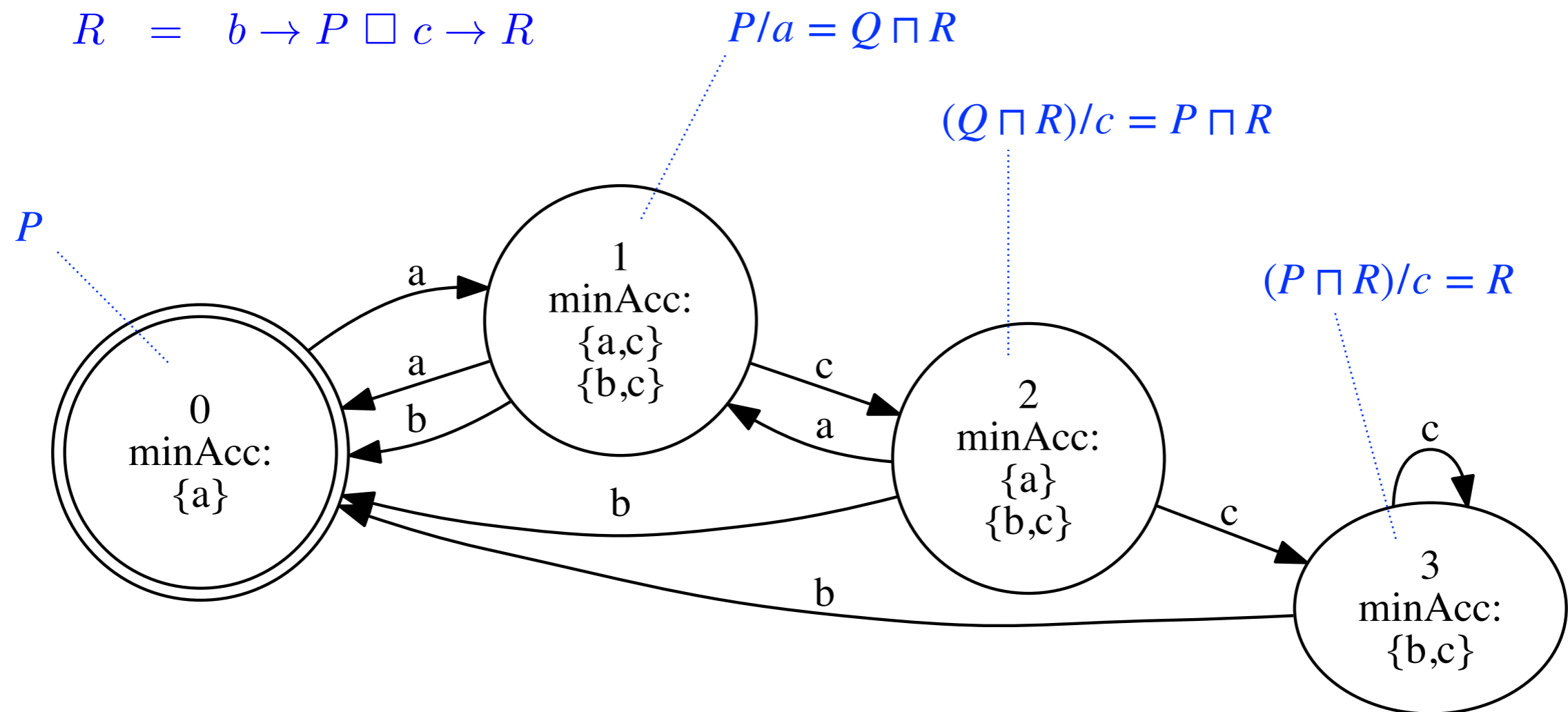


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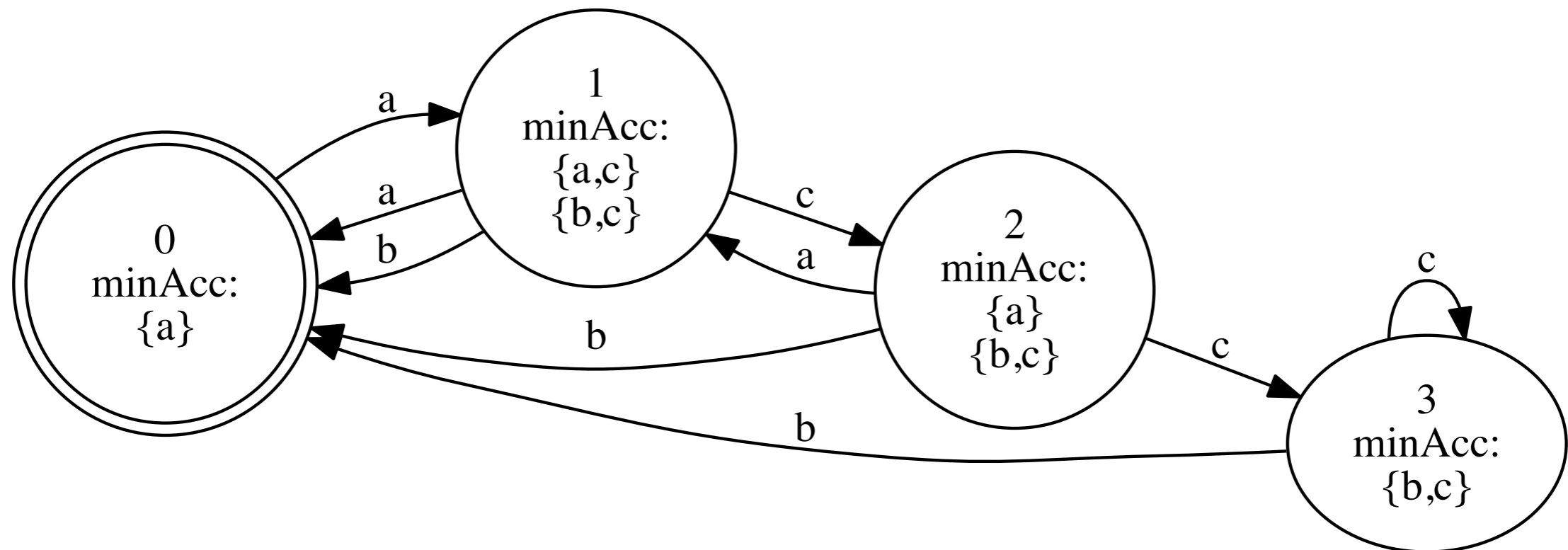
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**Assume that implementation process **Z** has transition graph with 4 states – just like **P****

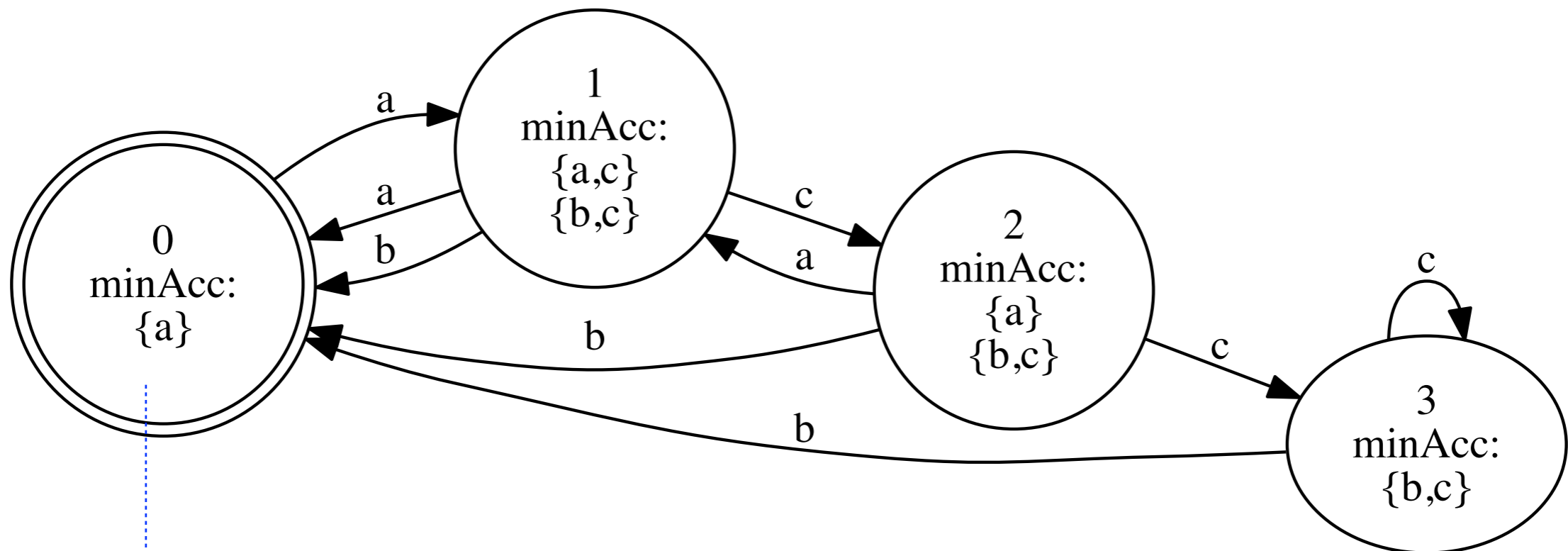


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**{a} must be a hitting set of  $acc(Z)$**

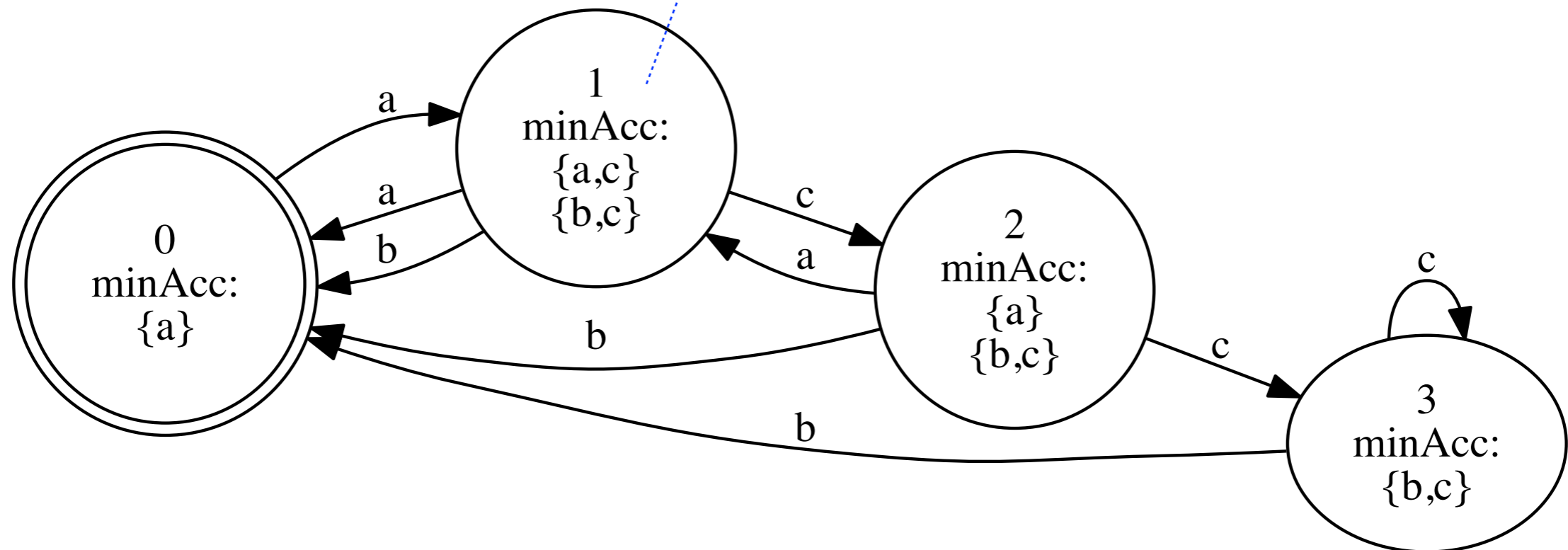
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$\{a, b\}, \{c\}$  must be hitting sets of  $acc(Z/a)$



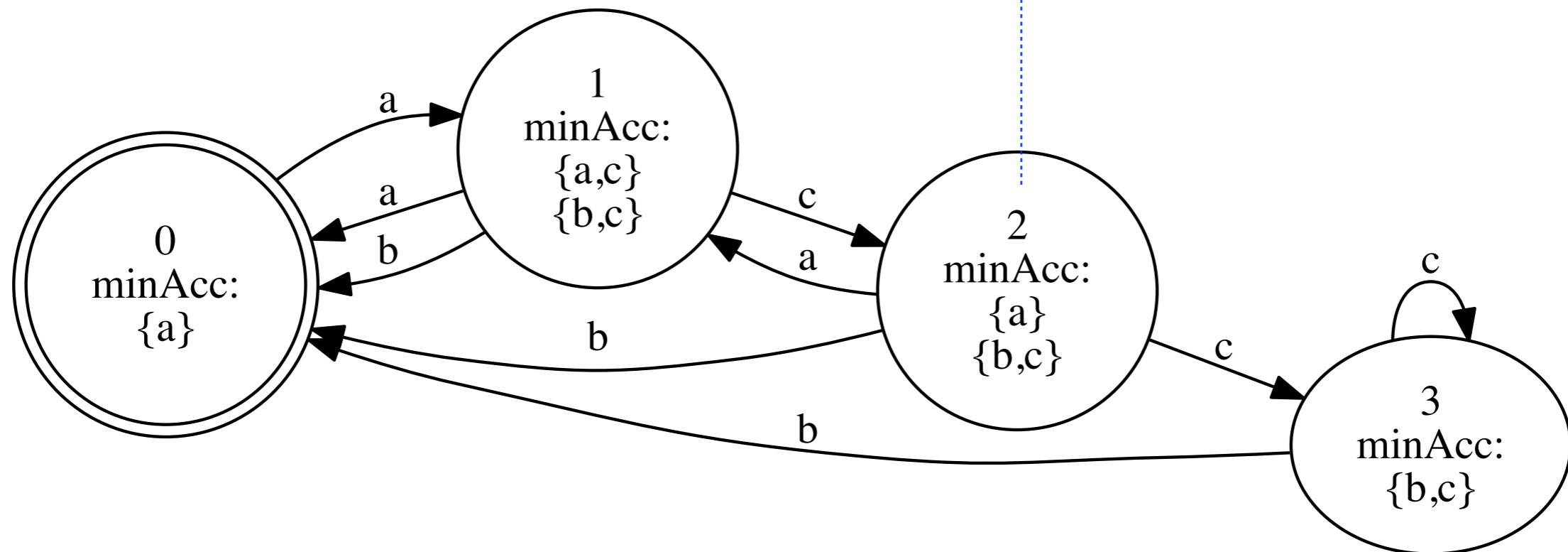
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$\{a, b\}, \{a, c\}$  must be hitting sets of  $acc(Z/a.c)$



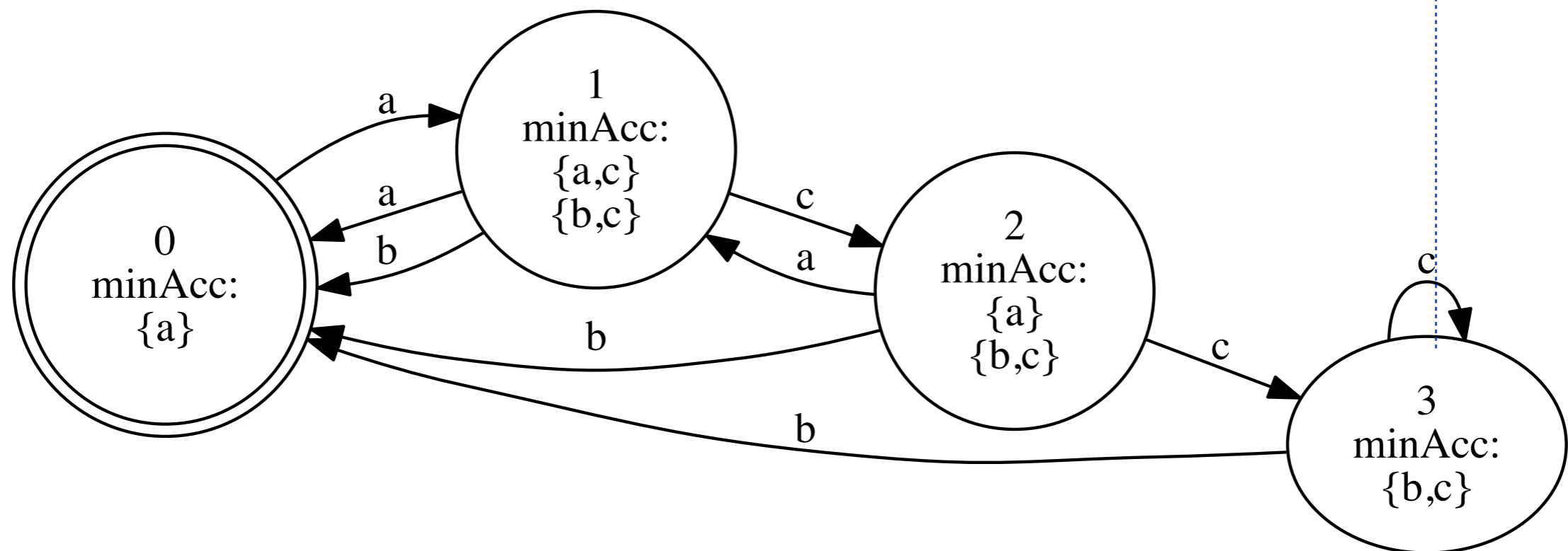
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$\{b\}, \{c\}$  must be hitting sets of  $acc(Z/a.c.c)$





# **Adaptive Test Cases for Checking Failures Refinement**

$$\begin{aligned}
U_F(j) &= U_F(j, 0, \underline{n}) \\
U_F(j, k, n) &= (e : (\Sigma - [n]^0) \rightarrow \text{fail} \rightarrow \mathbf{STOP}) \\
&\square \\
&(\text{minHit}(n) = \emptyset) \& (\text{pass} \rightarrow \mathbf{STOP}) \\
&\square \\
&(k < j) \& (e : [n]^0 \rightarrow U_F(j, k + 1, t(n, e))) \\
&\square \\
&(k = j \wedge \text{minHit}(n) \neq \emptyset) \& (\prod_{H \in \text{minHit}(n)} (e : H \rightarrow \text{pass} \rightarrow \mathbf{STOP}))
\end{aligned}$$

Check all traces up to length  $j+1$

$$U_F(j) = U_F(j, 0, \underline{n})$$

$$U_F(j, k, n) = (e : (\Sigma - [n]^0) \rightarrow \text{fail} \rightarrow \mathbf{STOP})$$

□

$$(\text{minHit}(n) = \emptyset) \& (\text{pass} \rightarrow \mathbf{STOP})$$

□

$$(k < j) \& (e : [n]^0 \rightarrow U_F(j, k + 1, t(n, e)))$$

□

$$(k = j \wedge \text{minHit}(n) \neq \emptyset) \& (\prod_{H \in \text{minHit}(n)} (e : H \rightarrow \text{pass} \rightarrow \mathbf{STOP}))$$

When residing in node  $n$  of  $P$ 's transition graph, ...

$$U_F(j) = U_F(j, 0, \underline{n})$$

$$U_F(j, k, n) = (e : (\Sigma - [n]^0) \rightarrow \text{fail} \rightarrow \mathbf{STOP})$$

□

$$(\text{minHit}(n) = \emptyset) \& (\text{pass} \rightarrow \mathbf{STOP})$$

□

$$(k < j) \& (e : [n]^0 \rightarrow U_F(j, k + 1, t(n, e)))$$

□

$$(k = j \wedge \text{minHit}(n) \neq \emptyset) \& (\prod_{H \in \text{minHit}(n)} (e : H \rightarrow \text{pass} \rightarrow \mathbf{STOP}))$$

... offer any illegal event to Q which should not be accepted

Initials of node  $n$

$$\begin{aligned} U_F(j) &= U_F(j, 0, \underline{n}) \\ U_F(j, k, n) &= (e : (\Sigma - [n]^0) \rightarrow \text{fail} \rightarrow \mathbf{STOP}) \\ &\square \\ &(\text{minHit}(n) = \emptyset) \& (\text{pass} \rightarrow \mathbf{STOP}) \\ &\square \\ &(k < j) \& (e : [n]^0 \rightarrow U_F(j, k + 1, t(n, e))) \\ &\square \\ &(k = j \wedge \text{minHit}(n) \neq \emptyset) \& (\prod_{H \in \text{minHit}(n)} (e : H \rightarrow \text{pass} \rightarrow \mathbf{STOP})) \end{aligned}$$

... allow to stop with verdict PASS if  $P$  allows to refuse everything at node  $n$

$$\begin{aligned} U_F(j) &= U_F(j, 0, \underline{n}) \\ U_F(j, k, n) &= (e : (\Sigma - [n]^0) \rightarrow \text{fail} \rightarrow \mathbf{STOP}) \\ &\square \\ &(\text{minHit}(n) = \emptyset) \& (\text{pass} \rightarrow \mathbf{STOP}) \\ &\square \\ &(k < j) \& (e : [n]^0 \rightarrow U_F(j, k + 1, t(n, e))) \\ &\square \\ &(k = j \wedge \text{minHit}(n) \neq \emptyset) \& (\prod_{H \in \text{minHit}(n)} (e : H \rightarrow \text{pass} \rightarrow \mathbf{STOP})) \end{aligned}$$

... continue with any event which is admissible according to  $n$ 's initials, as long as the trace is still shorter than  $j$ . Continue with the successor node of  $n$  according to  $P$ 's transition function  $t$  (*Back-to-Back Test Q against P*)

$$\begin{aligned}
 U_F(j) &= U_F(j, 0, \underline{n}) \\
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 \end{aligned}$$

... and check whether Q accepts an event from every minimal hitting set of node  $n$  without blocking, if the length of the trace is  $j$

$$\begin{aligned}
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 \end{aligned}$$



# PASS Criterion

- $Q$  passes test  $U_F(j)$ , if and only if for every possible execution of
  - no FAIL event is ever produced,
  - the test always terminates with PASS

$$Q \underline{pass} U_F(j) \equiv (pass \rightarrow \mathbf{STOP}) \sqsubseteq_F (Q \parallel_{\Sigma} U_F(j)) \setminus \Sigma$$

# Complete Testing Assumption

- There exists a constant  $c \geq 1$ , such that every possible behaviour of the SUT, when running in parallel to test case  $U$ , is exhibited within  $c$  executions of  $U$

# Completeness Result

**Theorem.** Let  $P$  be a non-terminating, divergence-free CSP process over alphabet  $\Sigma$  whose normalised transition graph  $G(P)$  has  $p$  states. Define fault domain  $\mathcal{D}$  as the set of all divergence-free CSP processes over alphabet  $\Sigma$ , whose transition graph has at most  $q$  states with  $q \geq p$ . Then the test suite

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is complete with respect to  $\mathcal{F} = (P, \sqsubseteq_F, \mathcal{D})$ .

# **Complexity Considerations**

# Maximal Number of Test Executions Required

**Theorem.** The maximal number of test executions to be performed using the complete test suite  $TS_F = \{U_F(j) \mid 0 \leq j < pq\}$  created from  $P$  is of order

$$O\left(\binom{n}{\lfloor \frac{n}{2} \rfloor} \cdot n^{pq-1}\right) \quad \text{with } n = |\Sigma|.$$

For processes  $P$  satisfying  $(s, \Sigma) \notin \text{failures}(P)$  for all traces  $s$ , the reachable precise upper bound is given by

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Maximal number of hitting sets to be tested at the end of each test execution

# Why we Cannot use Shorter Traces

**Theorem.** Let  $2 \leq p, q \in \mathbb{N}$ . Then there exists a reference process  $P$  and an implementation process  $Q$  with the following properties.

1.  $G(P)$  has  $p$  states.
2.  $G(Q)$  has  $q$  states.
3.  $P \not\sqsubseteq_T Q$ , and therefore, also  $P \not\sqsubseteq_F Q$ .
4.  $\forall s \in \text{traces}(Q) : \#s < pq \implies s \in \text{traces}(P)$ .
5.  $Q \text{ conf } P$ .

# Discussion



# Discussion

- **Could the test effort be further reduced?**
  - We know that maximal length of traces and number of probes  $H$  cannot be reduced without losing completeness
  - Translate results about adaptive state counting methods from FSMs to CSP

**R. M. Hierons**, Testing from a nondeterministic finite state machine using adaptive state counting, IEEE Trans. Computers 53 (10) (2004) 1330–1342. doi:10.1109/TC.2004.85

# Discussion

- Is it such a good idea to check for refinement?
  - From complete methods for FSMs we know that **complete equivalence checking** can be performed with much shorter traces: **maximal length  $p+q-1$**  (instead of  $pq - 1$  as required for refinement checking)
  - Alternative approach to be preferred:
    - refine original model and check correctness by model checker FDR4
    - Stop refinement as soon as implementation can be required to be equivalent to last refinement
    - Then **test for failures equivalence**

# Discussion

- **Implications for CSP model checking**
  - As an alternative to checking  $P \sqsubseteq_F Q$ , could it be effective to use an estimate for  $q$  and perform **concurrent** checks

$$(pass \rightarrow \mathbf{STOP}) \sqsubseteq_F (Q \parallel_{\Sigma} U_F(j)) \setminus \Sigma, \quad j = 0, \dots, pq - 1$$

# Acknowledgements

The authors would like to thank Bill Roscoe and Thomas Gibson-Robinson for their advice on using the FDR4 model checker and for very helpful discussions concerning the potential implications of this paper in the field of model checking. We are also grateful to Li-Da Tong from National Sun Yat-sen University, Taiwan, for suggesting the applicability of Sperner's Theorem in the context of the work presented here. Moreover, we thank Adenilso Simao for several helpful suggestions. The work of Ana Cavalcanti is funded by the Royal Academy of Engineering and UK EPSRC Grant EP/R025134/1.



# Appendix.

## Three

# Mathematical Tools

Product Graphs

Minimal Hitting sets

Sperner Families

# Product Graphs

$$G_1 \times G_2 = (N_1 \times N_2, (\underline{n}_1, \underline{n}_2), t : (N_1 \times N_2) \times \Sigma \rightarrow (N_1 \times N_2))$$

$$\text{dom } t = \{((n_1, n_2), e) \in (N_1 \times N_2) \times \Sigma \mid (n_1, e) \in \text{dom } t_1 \wedge (n_2, e) \in \text{dom } t_2\}$$

$$t((n_1, n_2), e) = (t_1(n_1, e), t_2(n_2, e)) \text{ for } ((n_1, n_2), e) \in \text{dom } t$$

# Product Graphs

Graph nodes are product of nodes of each operand

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# Product Graphs

Initial state is pair of  
operand's initial states

$$G_1 \times G_2 = (N_1 \times N_2, (\underline{n}_1, \underline{n}_2), t : (N_1 \times N_2) \times \Sigma \rightarrow (N_1 \times N_2))$$

$$\text{dom } t = \{((n_1, n_2), e) \in (N_1 \times N_2) \times \Sigma \mid (n_1, e) \in \text{dom } t_1 \wedge (n_2, e) \in \text{dom } t_2\}$$

$$t((n_1, n_2), e) = (t_1(n_1, e), t_2(n_2, e)) \text{ for } ((n_1, n_2), e) \in \text{dom } t$$

# Product Graphs

Transition function allows transition labelled by event  $e$  iff both “local” transition functions  $t_1, t_2$  allow for this transition from their respective source states

$$G_1 \times G_2 = (N_1 \times N_2, (\underline{n}_1, \underline{n}_2), t : (N_1 \times N_2) \times \Sigma \dashrightarrow (N_1 \times N_2))$$

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$$t((n_1, n_2), e) = (t_1(n_1, e), t_2(n_2, e)) \text{ for } ((n_1, n_2), e) \in \text{dom } t$$

# Lemma on Product Graph

**Lemma.** If  $G_1$  has  $p$  states and  $G_2$  has  $q$  states, then  $G_1 \times G_2$  has at most  $pq$  states, and every reachable state of  $G_1 \times G_2$  can be reached by a trace of maximal length  $pq - 1$ .

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**Lemma.** If  $G_1$  has  $p$  states and  $G_2$  has  $q$  states, then  $G_1 \times G_2$  has at most  $pq$  states, and every reachable state of  $G_1 \times G_2$  can be reached by a trace of maximal length  $pq - 1$ .

Apply this lemma as follows

- $G_1$  is the normalised transition graph of reference process  $P$
- $G_2$  is the (unknown) normalised transition graph of SUT with behaviour  $Q$
- **Hypothesis.**  $G_2$  has at most  $q \geq p$  states
- Suppose that  $Q$  exhibits faulty behaviour at some graph node  $n_2$ . Then
  - either this state can be reached by a trace of  $P$  with length  $< pq$ ,
  - or  $Q$  refuses to continue a shorter trace with an event which should not be refused according to reference process  $P$

# Minimal Hitting Sets

- Given a finite universe  $\Sigma$ , and a collection of subsets  $\{A_1, \dots, A_k\}$ , a subset  $H \subseteq \Sigma$  is called a **hitting set** of  $\{A_1, \dots, A_k\}$ , if and only if  $H \cap A_i \neq \{\}$  for all  $i = 1, \dots, k$
- A hitting set  $H$  is called **minimal**, if no true subset of  $H$  is a hitting set of  $\{A_1, \dots, A_k\}$

# Minimal Hitting sets of Minimal Acceptances Characterise *conf*

**Lemma.** Let  $P, Q$  be two finite-state CSP processes. For each  $s \in \text{traces}(P)$ , let  $\text{minHit}(P/s)$  denote the collection of all minimal hitting sets of  $\text{minAcc}(P/s)$ . Then the following statements are equivalent.

1.  $Q \text{ conf } P$
2. For all  $s \in \text{traces}(P) \cap \text{traces}(Q)$  and  $H \in \text{minHit}(P/s)$ ,  $H$  is a (not necessarily minimal) hitting set of  $\text{minAcc}(Q/s)$ .

# Sperner Families

- **Sperner Family.** A collection of subsets of finite universe  $\Sigma$ , such that no pair of distinct sets in the family are in subset relation

$$\{A_1, \dots, A_k\} \subseteq 2^\Sigma, \quad \forall i \neq j : A_i \not\subseteq A_j \wedge A_j \not\subseteq A_i$$

- **Sperner's Theorem.** The cardinality of a Sperner family is bounded by

$$\binom{n}{\lfloor \frac{n}{2} \rfloor} \quad \text{with} \quad n = |\Sigma|$$

# Sperner Families

- **Sperner Family.** A collection of subsets of finite universe  $\Sigma$ , such that no pair of distinct sets in the family are in subset relation

This maximum is reached

- For even  $n$ : all subsets of  $\Sigma$  with cardinality  $n/2$
- For odd  $n$  : all subsets of  $\Sigma$  with cardinality  $(n-1)/2$
- For odd  $n$  : all subsets of  $\Sigma$  with cardinality  $(n+1)/2$

- **Sperner's Theorem.** The cardinality of a Sperner family is bounded by

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# Sperner Families in our Context

- Maximal refusals of a process state
- Minimal acceptances of a process state
- Minimal hitting sets

**Appendix.**  
**Semantics of CSP,**  
**Refusals and Acceptances**

# Overview

- A new result: **finite** complete test suites for CSP conformance relations
  - **traces refinement**
  - **failures refinement**
- Complexity bounds
- Presentation of methods that are universally applicable for arbitrary formalisms

# CSP

Nondeterministic communicating sequential processes over finite alphabets

Deadlock process

**STOP**

Prefixing with events

$a \rightarrow b \rightarrow c \rightarrow \mathbf{STOP}$

Process equations  
with recursion

$P = a \rightarrow Q$

$Q = b \rightarrow P$

External choice

$P = (a \rightarrow P \square b \rightarrow c \rightarrow P)$

Internal choice

$P = (a \rightarrow P \sqcap b \rightarrow c \rightarrow P)$

Concurrent processes  
synchronised over set  
of events

$P \parallel \{a, b, c\} \parallel Q$

# CSP Traces Semantics

- $\text{traces}(P)$  – language generated by CSP process  $P$
- Prefix-closed  $\text{traces}(a \rightarrow b \rightarrow \mathbf{STOP}) = \{\varepsilon, a, a.b\}$
- Denotational traces semantics provides compositional rules about how to compute the traces of a composed processes, provided that the traces of the operands are known  
 $\text{traces}(P \sqcap Q) = \text{traces}(P) \cup \text{traces}(Q)$

# CSP Failures Semantics

- **Refusal.** A set of events that may be refused in a certain process state  $P/s$  ( $= P$ , after having run through trace  $s$ )
  - Refusals are subset-closed
  - All refusals of a process state can be calculated from its maximal refusals, due to subset closure
- **Failure.** A pair  $(s, R)$ , such that  $R$  is a refusal of  $P/s$
- **failures(P)** can be calculated via compositional rules of the denotational semantics

# Example

## Rule

$$\mathbf{failures}(\mathbf{STOP}) = \{(\varepsilon, R) \mid R \subseteq \Sigma\}$$

## Rule

$$\mathbf{failures}(a \rightarrow P) = \{(\varepsilon, R) \mid R \subseteq \Sigma - \{a\}\} \cup \{(a.s, R) \mid (s, R) \in \mathbf{failures}(P)\}$$

## Conclusion

$$\mathbf{failures}(a \rightarrow \mathbf{STOP}) = \{(\varepsilon, R) \mid R \subseteq \Sigma - \{a\}\} \cup \{(a, R) \mid R \subseteq \Sigma\}$$

# Conformance Relations in CSP

- **Trace refinement**  $P \sqsubseteq_T Q \equiv \text{traces}(Q) \subseteq \text{traces}(P)$
- **Trace equivalence**  $P =_T Q \equiv \text{traces}(Q) = \text{traces}(P)$
- **Failures refinement**  $P \sqsubseteq_F Q \equiv \text{failures}(Q) \subseteq \text{failures}(P)$
- **Failures equivalence**  $P =_F Q \equiv \text{failures}(Q) = \text{failures}(P)$



# Auxiliary Conformance Relation

$$Q \text{ conf } P \equiv \forall s \in \mathbf{traces}(P) \cap \mathbf{traces}(Q) : \mathbf{Ref}(Q/s) \subseteq \mathbf{Ref}(P/s)$$

**Lemma.**  $P \sqsubseteq_F Q \Leftrightarrow P \sqsubseteq_T Q \wedge Q \text{ conf } P$

**A. Cavalcanti, M. Gaudel,** Testing for refinement in CSP, in: M. J. Butler, M. G. Hinchey, M. M. Larrondo-Petrie (Eds.), Formal Methods and Software Engineering, 9th International Conference on Formal Engineering Methods, ICFEM 2007, Boca Raton, FL, USA, November 14-15, 2007, Proceedings, Vol. 4789 of Lecture Notes in Computer Science, Springer, 2007, pp. 151–170. doi: 10.1007/978-3-540-76650-6\\_10.

**J. Tretmans.** A formal approach to conformance testing. PhD thesis, University of Twente, Enschede, The Netherlands, 1992.

# Acceptances vs. Refusals

- A set of events  $A$  is an **acceptance** of process state, if  $A$  is the complement of a refusal  $R$  in this state

$$A = \Sigma - R$$

- A **minimal acceptance** is a complement of a maximal refusal

- **Saturation property:**  $A$  is an acceptance of a process state  $P/s$ , if  $A$  is

- a superset of some minimal acceptance, and
- a subset of the state's initials  $[P/s]^0$

$$A_{min} \subseteq A \subseteq [P/s]^0$$